

Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from, Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



## Contact us

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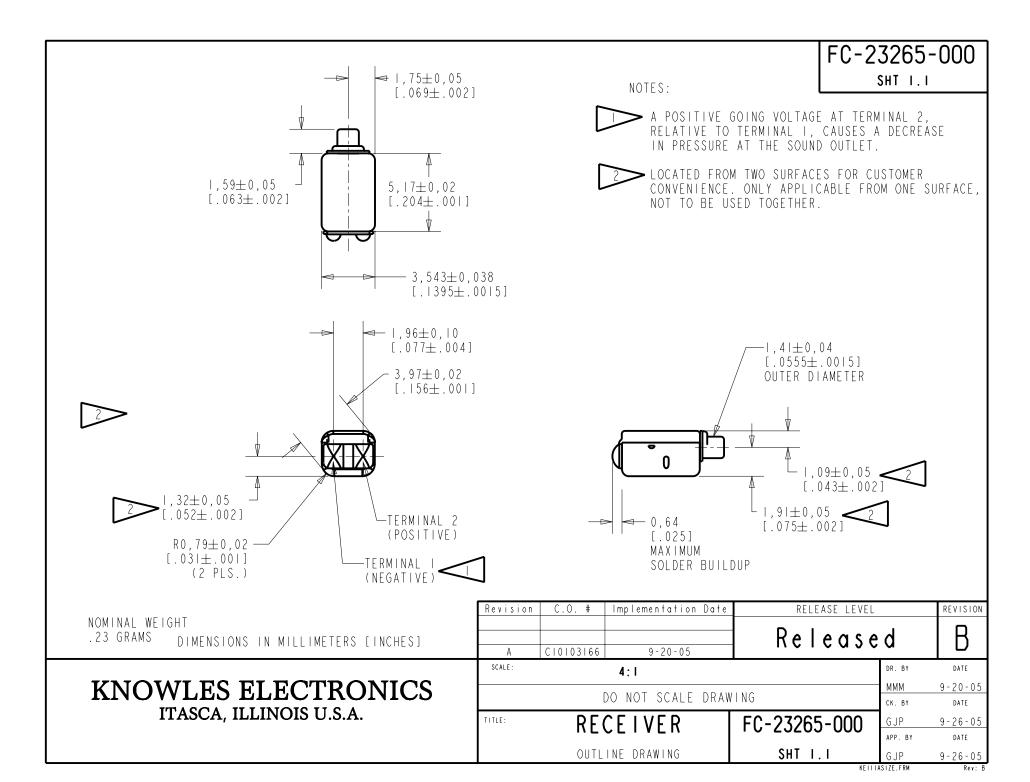
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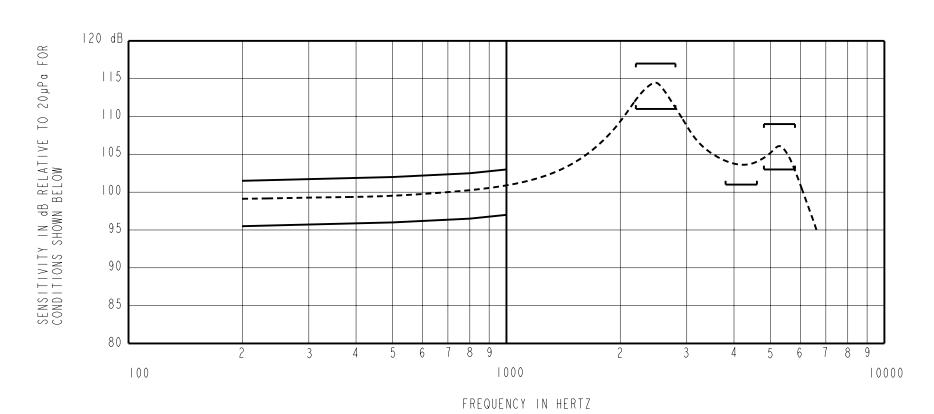
Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China











## NOTES:

I. MEASUREMENTS MADE USING 10mm (.394") X 1mm (.039") 1D TUBE CONNECTED TO A SIMULATED ANSI S3.3-1960 TYPE HA-3 COUPLER. (T3420 AND B & K DB0138).

2.		SENSITIVITY	
	FREQUENCY	MIN.	MAX.
	200 500 800 1000	95.5 96.0 96.5 97.0	101.5 102.0 102.5 103.0
	2200 - 2800 3800 - 4600 4800 - 5800	.0  0 .0  03.0	117.0

- 3. RESPONSE, IMPEDANCE, AND DISTORTION MEASUREMENTS MADE USING THE ELECTRICAL TEST CONDITIONS SHOWN BELOW.
- 4. ELECTRICAL SOURCE IMPEDANCE MUST BE GREATER THAN 20 TIMES IKHZ IMPEDANCE FOR TEST CONDITIONS SHOWN BELOW.
- 5. INDIVIDUAL SPECIFICATIONS.

PORT LOCATION	IMPEDANCE OHMS ±15%		DCR @20°C	DISTORTION		ELECTRICAL TEST CONDITIONS	
	IKHz	500Hz	OHMS ±10%	MAX. %	FREQ Hz	AC mA RMS	DC mA
12C	1055	625	395	10	800	0.71	0.00

Kevision	C.O. #	Implementation Date	Released		KEA1210M
					R
А	C10103166	9 - 20 - 05			
			INSPECTION ACCEPTANCE/REJECTION	DR. BY	DATE
		DF TEST EQUIPMENT WITH KN NT AND TEST METHOD VARIAT	OWLES IS ALSO REQUIRED FOR ION	MMM	9 - 20 - 05

	, CORRELATION OF TEST EQUIPMENT WITH KNOW ON OF EQUIPMENT AND TEST METHOD VARIATION		MMM ck. By	9 - 20 - 05 DATE
TITLE:	RECEIVER	FC-23265-000	GJP APP. BY	9 - 26 - 05 DATE
	PERFORMANCE SPECIFICATION	SHT 2 I	C ID	0 26 05